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(54) **INTEGRATED CIRCUIT DEVICE WITH EMBEDDED PROGRAMMABLE LOGIC**

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CPC **G06F 13/1689** (2013.01); **G06F 13/4068** (2013.01); **G06F 13/42** (2013.01); **G11C 7/22** (2013.01); **G11C 8/00** (2013.01); **G11C 29/12** (2013.01); **H01L 23/5381** (2013.01); **H01L 23/5384** (2013.01); **H01L 23/5386** (2013.01);
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None
See application file for complete search history.

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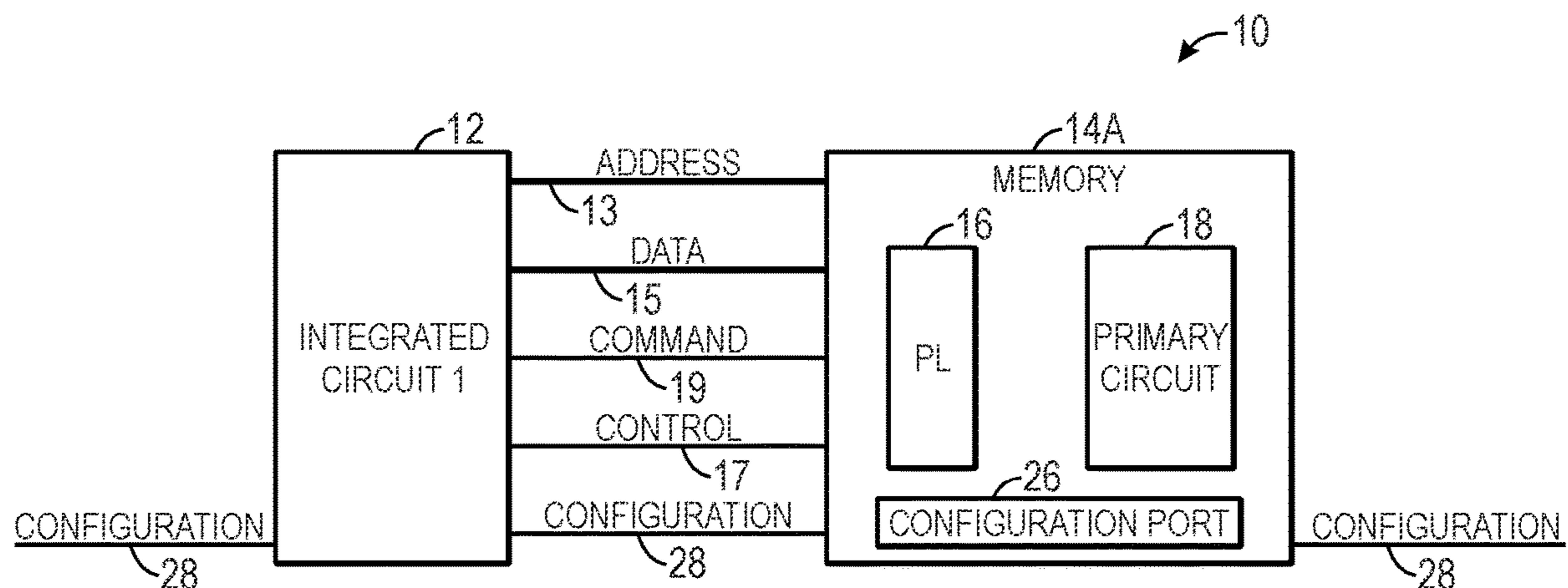
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(57) **ABSTRACT**

Systems and methods are provided to enhance the functionality of an integrated circuit. Such an integrated circuit may include a primary circuitry and an embedded programmable logic programmable to adjust the functionality of the primary circuitry. Specifically, the embedded programmable logic may be programmed to adjust the functionality of the primary circuitry to complement and/or support the functionality of another integrated circuit. Accordingly, the embedded programmable logic may be programmed with functions such as data/address manipulation functions, configuration/testing functions, computational functions, or the like.

20 Claims, 5 Drawing Sheets



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continuation of application No. 16/378,356, filed on Apr. 8, 2019, now Pat. No. 10,719,460, which is a continuation of application No. 15/422,310, filed on Feb. 1, 2017, now Pat. No. 10,296,474, which is a continuation of application No. 14/602,131, filed on Jan. 21, 2015, now Pat. No. 9,589,612, which is a continuation of application No. 13/913,096, filed on Jun. 7, 2013, now Pat. No. 9,136,842.

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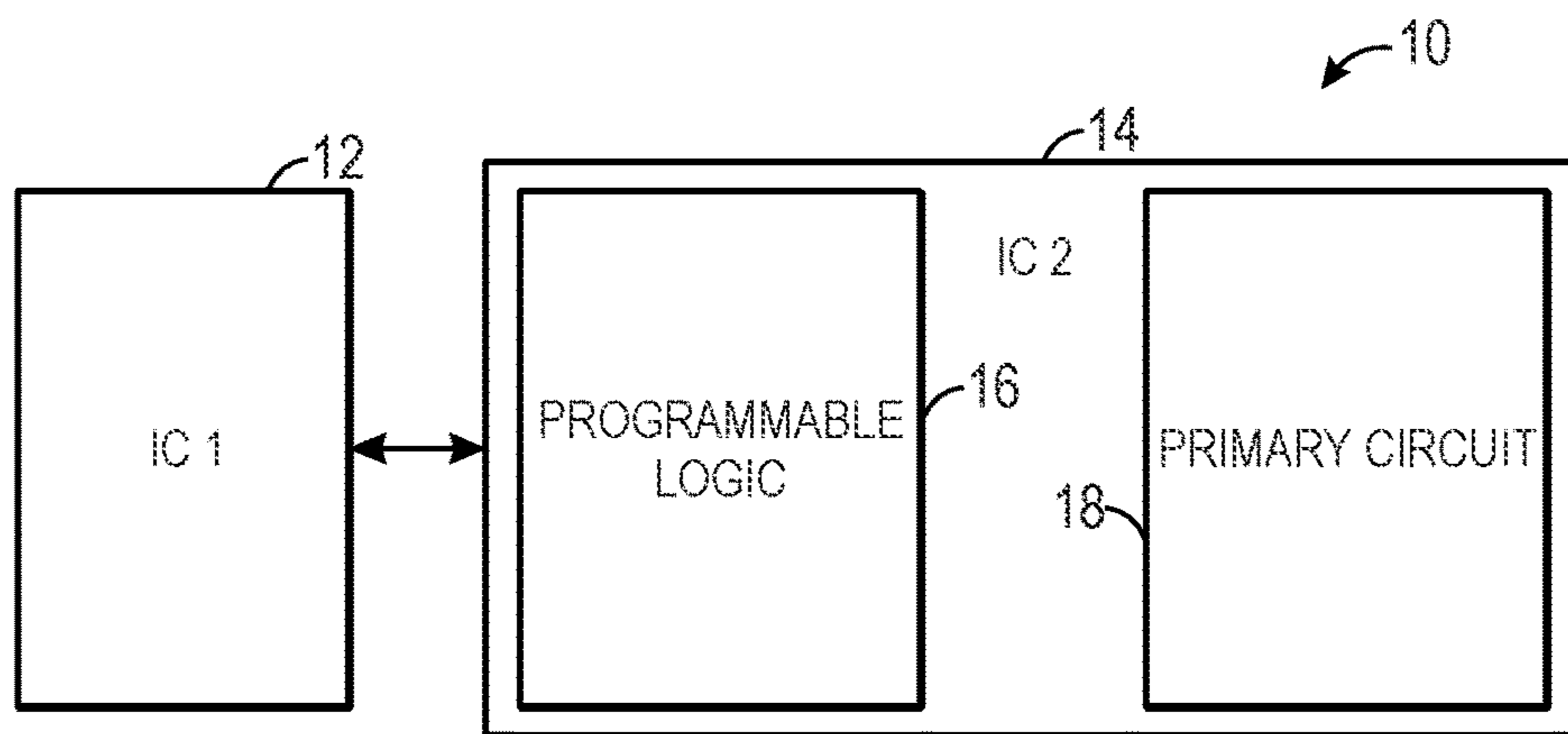


FIG. 1

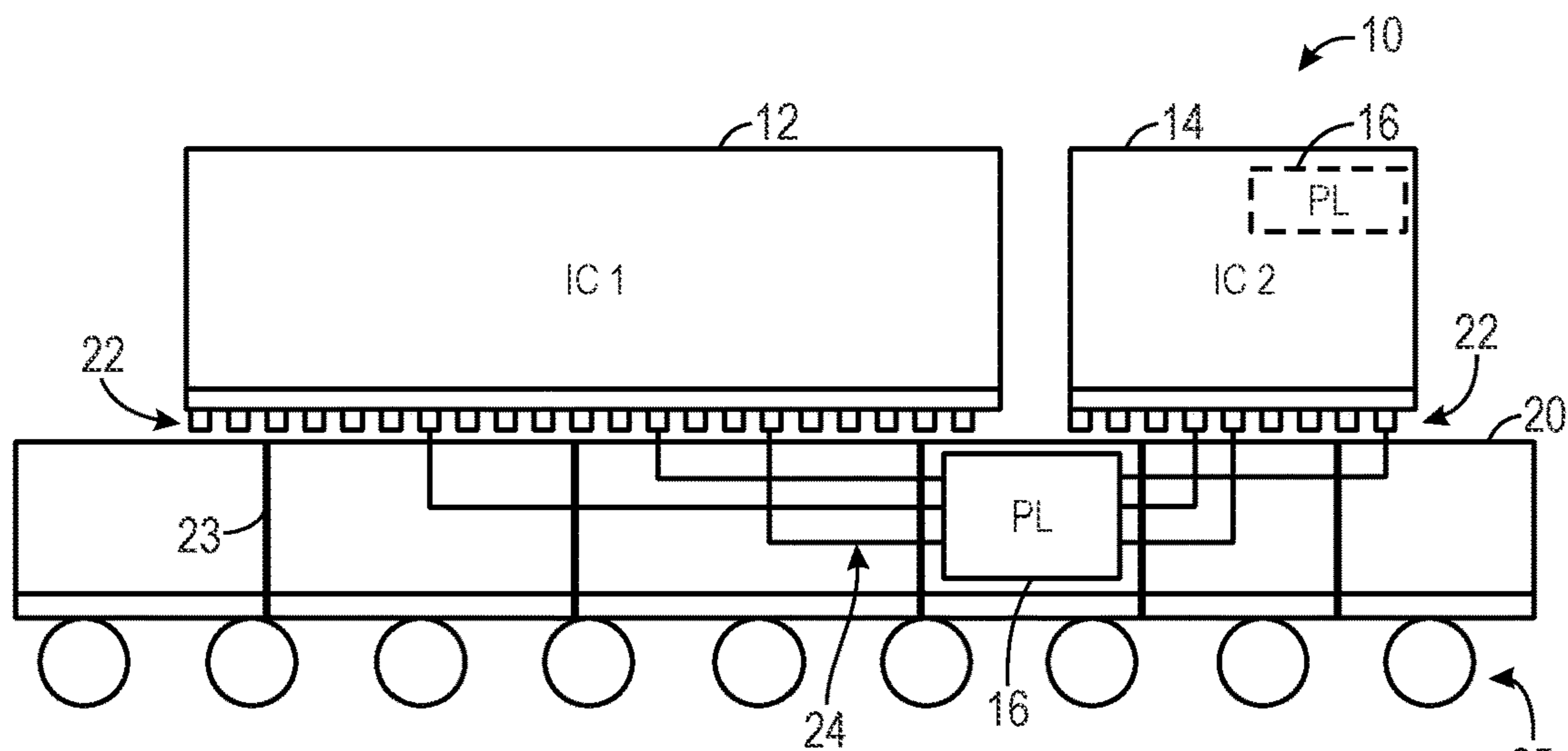


FIG. 2

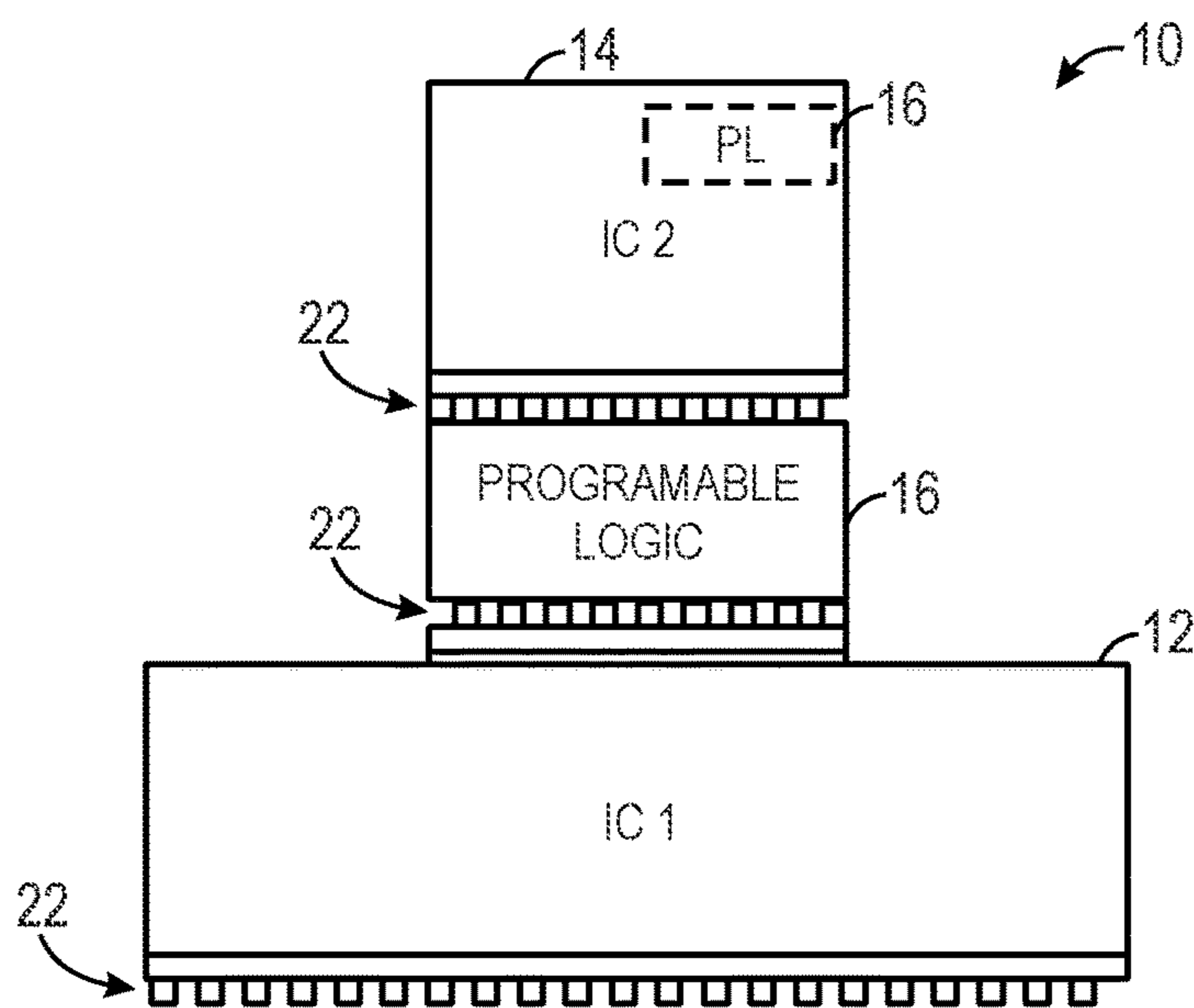


FIG. 3

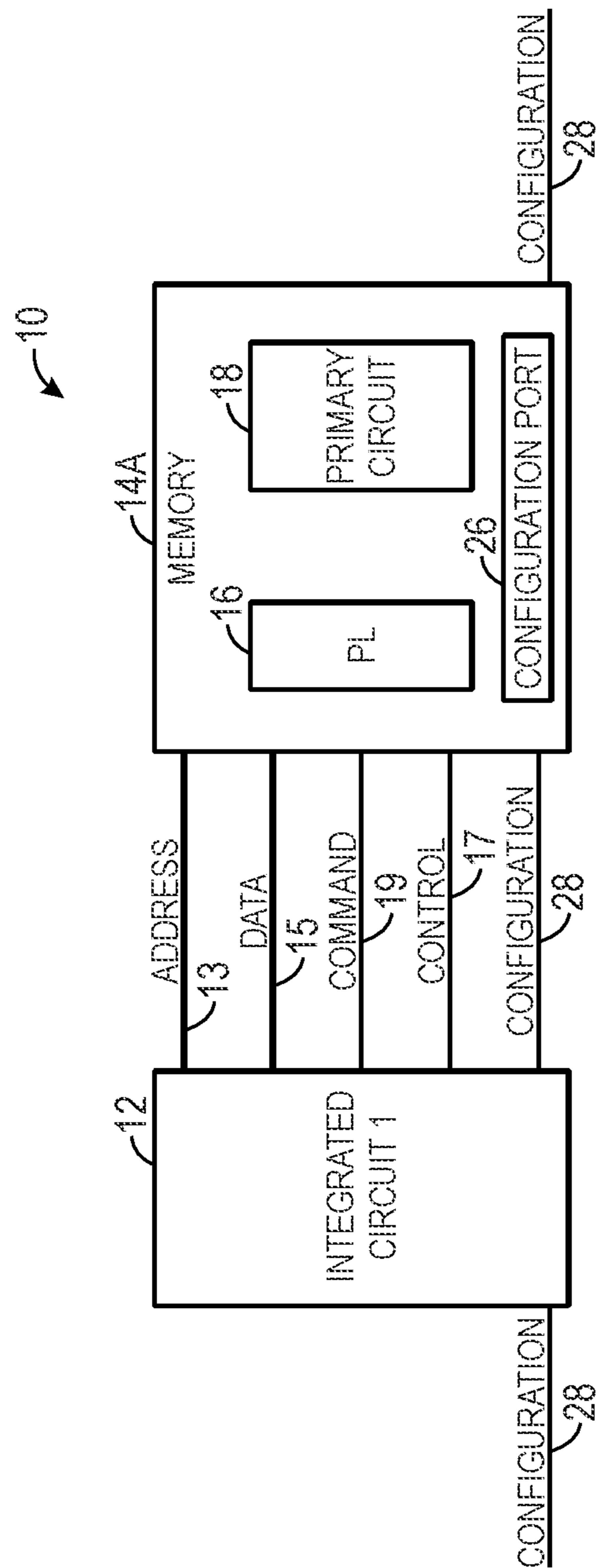


FIG. 4

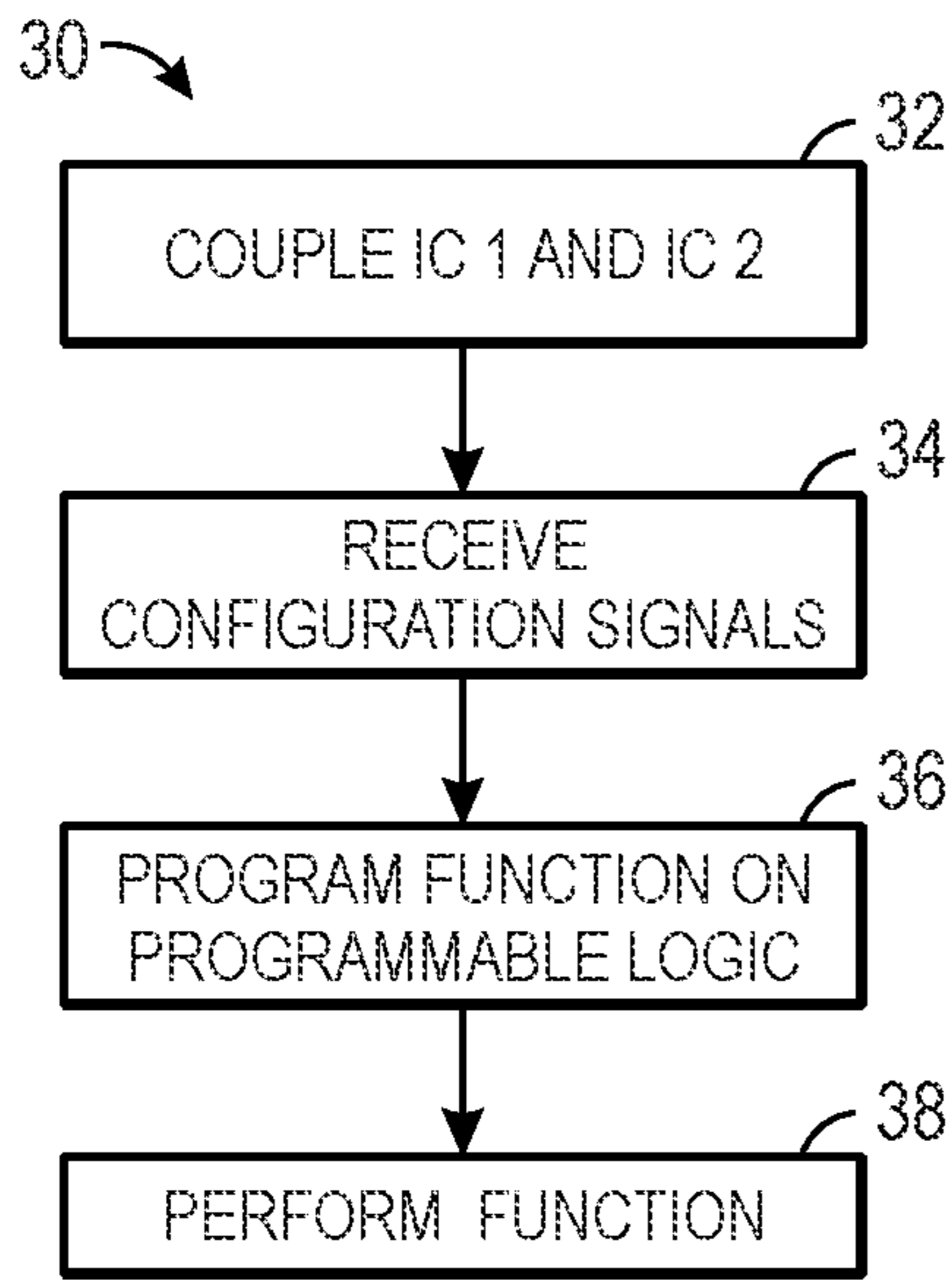


FIG. 5

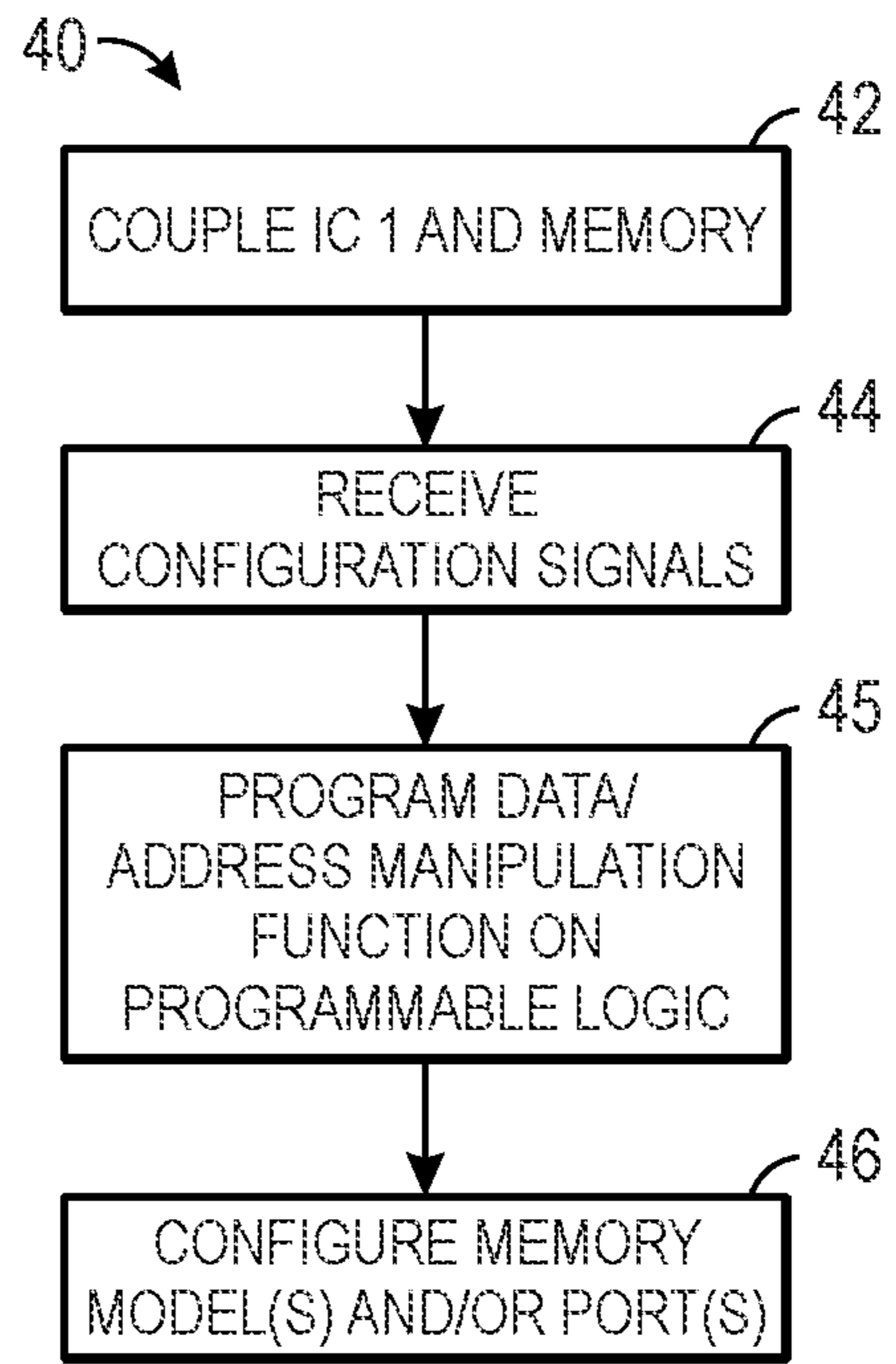


FIG. 6

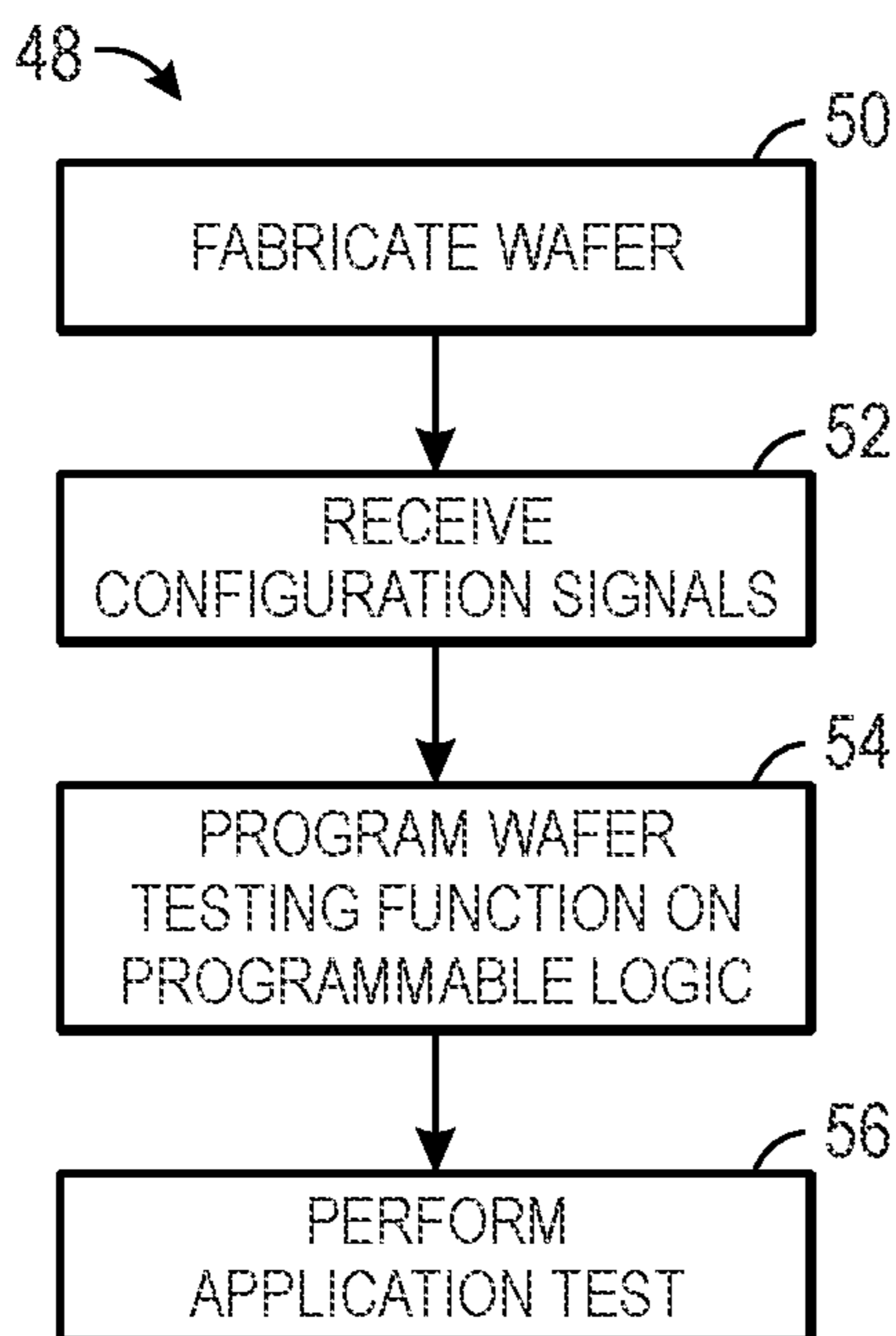


FIG. 7

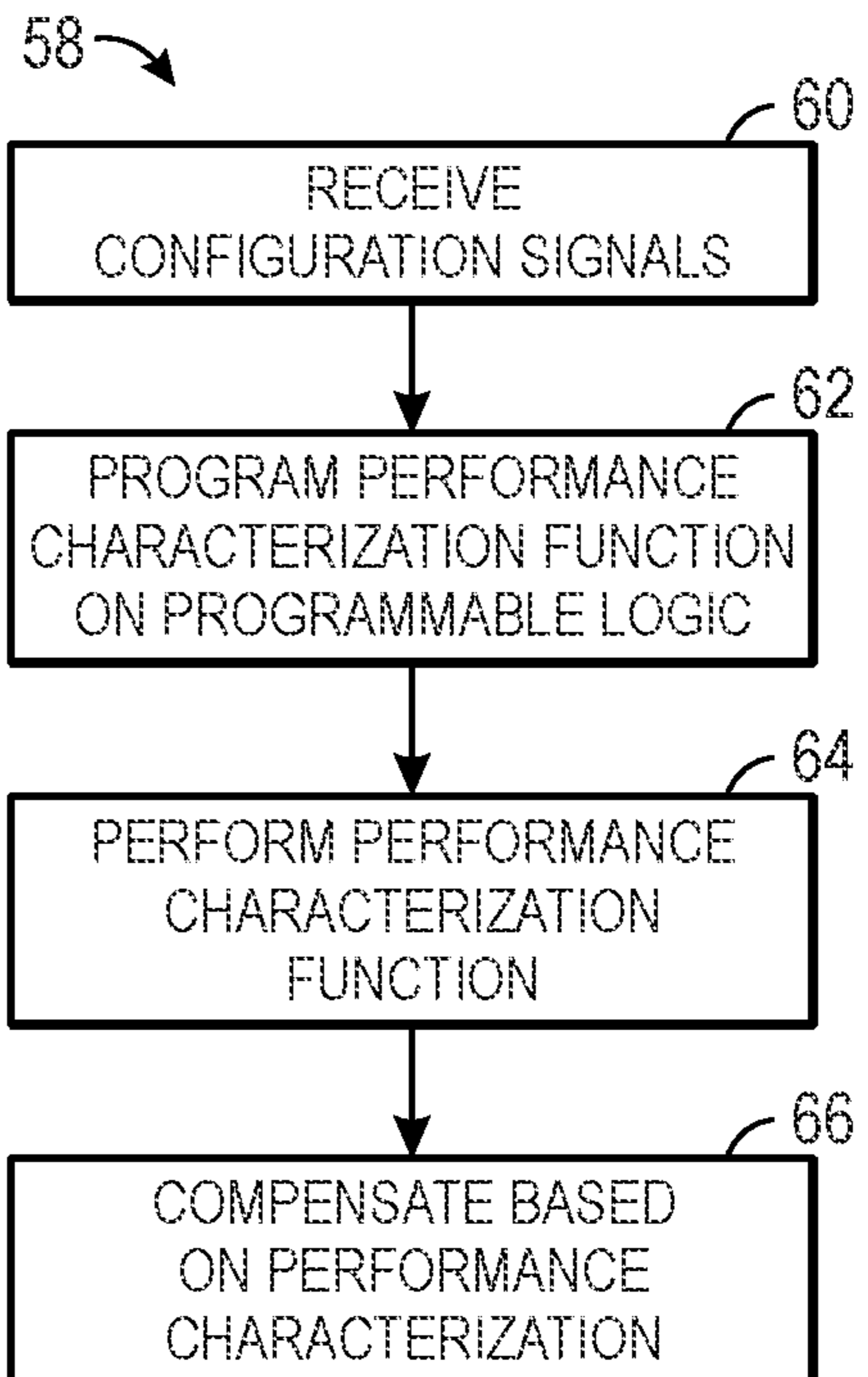


FIG. 8

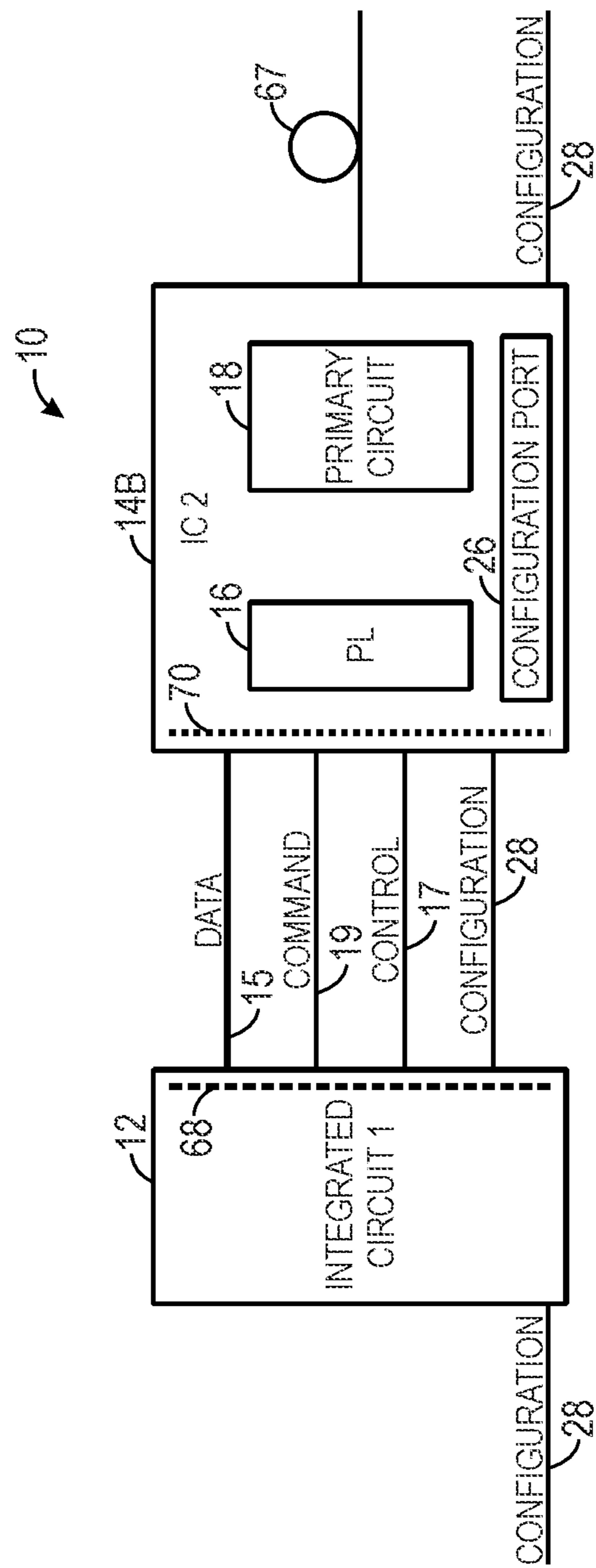


FIG. 9

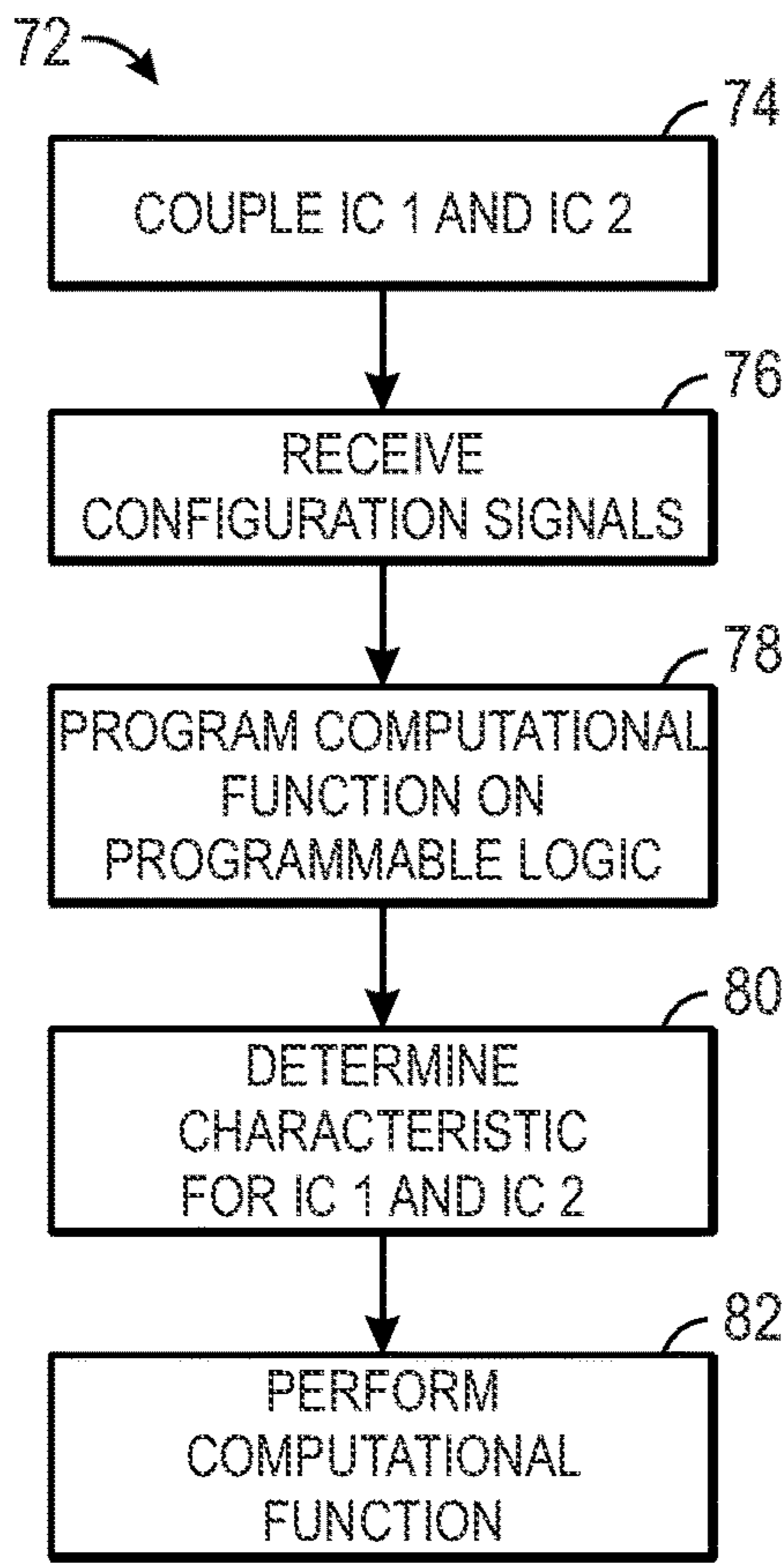


FIG. 10

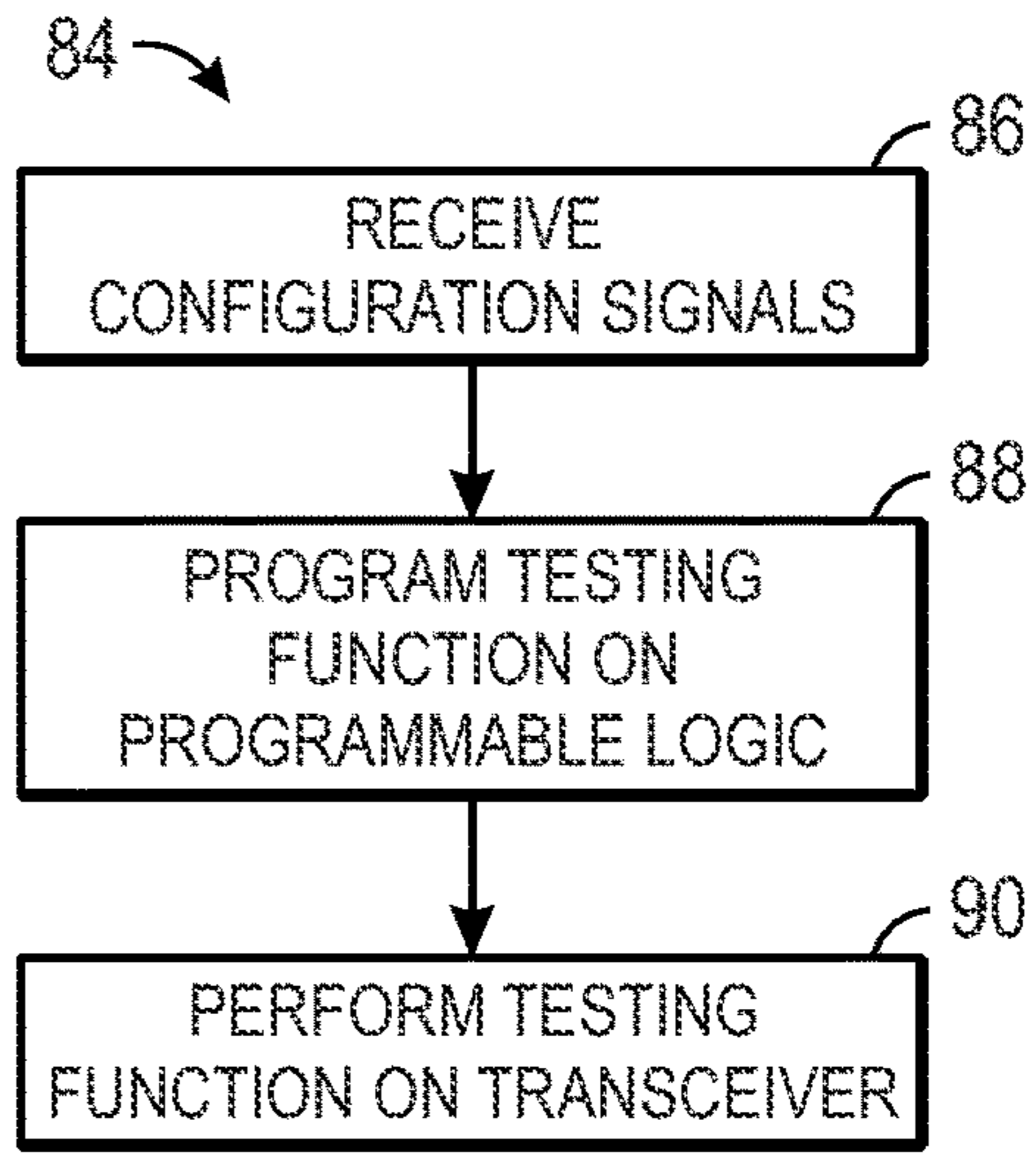


FIG. 11

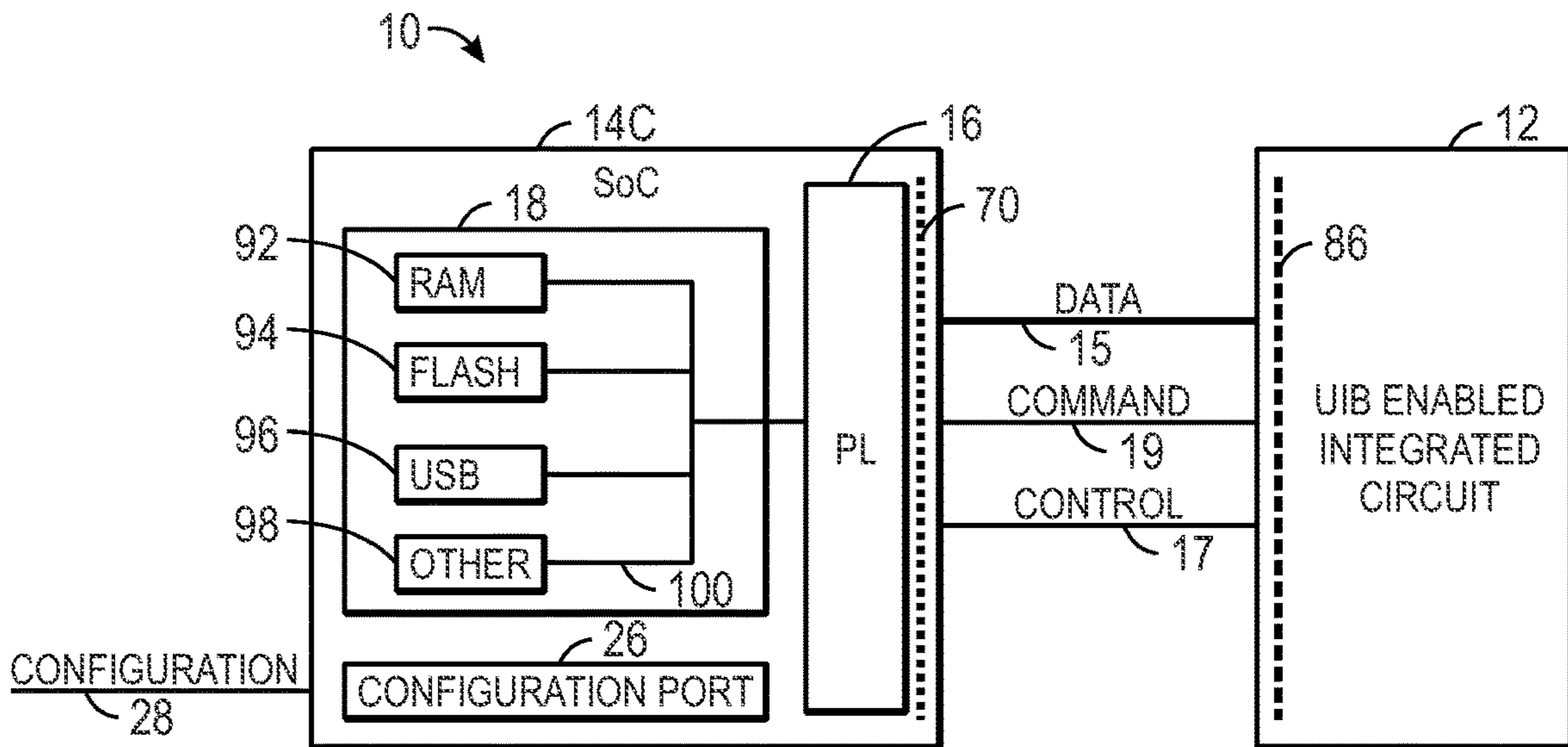


FIG. 12

INTEGRATED CIRCUIT DEVICE WITH EMBEDDED PROGRAMMABLE LOGIC

CROSS-REFERENCE TO RELATED APPLICATIONS

Under 35 U.S.C. § 120, this application is a continuation of U.S. patent application Ser. No. 16/933,628 filed on Jul. 20, 2020, which is a continuation of U.S. patent application Ser. No. 16/378,356 filed on Apr. 8, 2019, now U.S. Pat. No. 10,719,460, which is a continuation of U.S. patent application Ser. No. 15/422,310 filed on Feb. 1, 2017, now U.S. Pat. No. 10,296,474, which is a continuation of U.S. patent application Ser. No. 14/602,131 filed on Jan. 21, 2015, now U.S. Pat. No. 9,589,612, which is a continuation of U.S. patent application Ser. No. 13/913,096 filed on Jun. 7, 2013, now U.S. Pat. No. 9,136,842, each of which is incorporated by reference herein in its entirety for all purposes.

BACKGROUND

This disclosure relates to integrated circuit devices and, more particularly, integrated circuit devices configured through programmable logic embedded within the integrated circuit devices.

This section is intended to introduce the reader to various aspects of art that may be related to various aspects of these techniques, which are described and/or claimed below. This discussion is believed to be helpful in providing the reader with background information to facilitate a better understanding of the various aspects of this disclosure. Accordingly, it should be understood that these statements are to be read in this light, and not as admissions of prior art.

Integrated circuits are found in a variety of electronic systems. Computers, handheld devices, portable phones, televisions, industrial control systems, and robotics, to name just a few, rely on integrated circuits. For example, a first integrated circuit, such as a field programmable gate array (FPGA), may communicate with a second integrated circuit, such as memory, to carry out certain data processing. In another example, an application-specific integrated circuit (ASIC) may communicate with an optical module to carry out certain data processing.

As technology advances, it is not uncommon for integrated circuits to quickly become out-dated. For example, an industry standard, such as standards for chip-to-chip interfaces, may change. Specifically, this may include changing from a first universal interface block (UIB1) to a second universal interface block (UIB2). In such a case, an integrated circuit utilizing UIB1 may be redesigned to utilize UIB2, which, because of the added cost of redesigning the integrated circuit, may increase the overall cost in producing the integrated circuit. In addition, as described above, integrated circuit devices are utilized in many devices, which may each have specific functional requirements. Accordingly, instead of redesigning the entire integrated circuit, it may be desirable to enhance the functionality of the base integrated circuit.

SUMMARY

A summary of certain embodiments disclosed herein is set forth below. It should be understood that these aspects are presented merely to provide the reader with a brief summary of these certain embodiments and that these aspects are not

intended to limit the scope of this disclosure. Indeed, this disclosure may encompass a variety of aspects that may not be set forth below.

Embodiments of this disclosure relate to systems and methods involving enhancing the functionality of an integrated circuit. To enhance the functionality, the integrated circuit may include an embedded programmable logic that is programmable to adjust the functionality of the primary circuitry of the integrated circuit. In this disclosure, the primary circuitry describes the base functionality of the integrated circuit. Specifically, the programmable logic may be programmed through configuration signals received from another integrated circuit and/or a computing device. Thus, the integrated circuit may complement and/or support the functionality of another integrated circuit by being programmed with functions such as data/address manipulation functions, configuration/testing functions, computational functions or the like.

Various refinements of the features noted above may be made in relation to various aspects of this disclosure. Further features may also be incorporated in these various aspects as well. These refinements and additional features may be made individually or in any combination. For instance, various features discussed below in relation to one or more of the illustrated embodiments may be incorporated into any of the above-described aspects of this disclosure alone or in any combination. The brief summary presented above is intended only to familiarize the reader with certain aspects and contexts of embodiments of this disclosure without limitation to the claimed subject matter.

BRIEF DESCRIPTION OF THE DRAWINGS

Various aspects of this disclosure may be better understood upon reading the following detailed description and upon reference to the drawings in which:

FIG. 1 is a block diagram of a system that includes a first integrated circuit device communicatively coupled to a second integrated circuit with a programmable logic and a primary circuit, in accordance with an embodiment;

FIG. 2 is a side view of a block diagram of the first integrated circuit and the second integrated circuit of FIG. 1 communicatively coupled, in accordance with an embodiment;

FIG. 3 is a side view of a block diagram of the first integrated circuit and the second integrated circuit of FIG. 1 communicatively coupled, in accordance with an embodiment;

FIG. 4 is a block diagram of the first integrated circuit communicatively coupled to memory, in accordance with an embodiment;

FIG. 5 is a flow chart depicting a process for utilizing the second integrated circuit to enhance the functionality of a first integrated circuit, in accordance with an embodiment;

FIG. 6 is a flowchart depicting a process for configuring memory modes and/or memory, in accordance with an embodiment;

FIG. 7 is a flowchart depicting a process for performing wafer testing, in accordance with an embodiment;

FIG. 8 is a flowchart depicting a process for compensating for the age of the memory, in accordance with an embodiment;

FIG. 9 is a block diagram of the first integrated circuit with a first universal interface block (UIB1) communicatively coupled to a second integrated circuit with a second universal interface block (UIB2), in accordance with an embodiment;

FIG. 10 is a flowchart depicting a process for performing computational functions (e.g., interfacing functions) between the first integrated circuit and the second integrated circuit, in accordance with an embodiment;

FIG. 11 is a flow chart depicting a process for performing testing functions on a transceiver, in accordance with an embodiment; and

FIG. 12 is a block diagram of a system-on-a-chip (SoC) with the first universal interface block (UIB1) communicatively coupled to a second integrated circuit with the second universal interface block (UIB2), in accordance with an embodiment.

DETAILED DESCRIPTION

One or more specific embodiments of this disclosure will be described below. These described embodiments are only examples of the disclosed techniques. Additionally, in an effort to provide a concise description of these embodiments, all features of an actual implementation may not be described in the specification. It should be appreciated that in the development of any such actual implementation, as in any engineering or design project, numerous implementation-specific decisions must be made to achieve the developers' specific goals, such as compliance with system-related and business-related constraints, which may vary from one implementation to another. Moreover, it should be appreciated that such a development effort might be complex and time consuming, but may nevertheless be a routine undertaking of design, fabrication, and manufacture for those of ordinary skill having the benefit of this disclosure.

When introducing elements of various embodiments of this disclosure, the articles "a," "an," and "the" are intended to mean that there are one or more of the elements. The terms "comprising," "including," and "having" are intended to be inclusive and mean that there may be additional elements other than the listed elements. Additionally, it should be understood that references to "one embodiment" or "an embodiment" of this disclosure are not intended to be interpreted as excluding the existence of additional embodiments that also incorporate the recited features.

This disclosure generally relates to integrated circuits with embedded programmable logic that enables enhanced functionality in the integrated circuits. Integrated circuits are included in a wide range of devices, such as computers, handheld devices, portable phones, televisions, industrial control systems, robotics, and the like. As such, each of the different devices may have slightly different functionality requirements. For example, a first device may desire for the integrated circuit device, such as memory, to have three read ports and one write port; however, a second device may desire for the integrated circuit to have two read ports and two write points. Thus, the functionality of the integrated circuit in this example may differ slightly.

In addition, as technology advances, the standards and protocols used in devices may also advance. For example, an older integrated circuit may utilize a first universal interface block (UIB1), whereas a newer integrated circuit may utilize an updated second universal interface block (UIB2). As such, it may be difficult to properly interface the older integrated circuit and the newer integrated circuit because of the differing versions of the universal interface block.

Accordingly, the present disclosure includes a programmable logic embedded in an integrated circuit, in which the programmable logic is programmed to increase the functionality of the integrated circuit. Specifically, the functionality of the integrated circuit is increased by implementing

data/address manipulation functions, configuration/testing functions, computational functions, or any combination thereof. As used herein, data/address manipulation functions describe access functions, such as incrementing/decrementing memory addresses; configuration/testing functions describe manufacturing and design functions, such as wafer testing integrated circuits; and computational functions describe application specification functions, such as protocol translation and analytics. In other words, programmable logic may be embedded within the integrated circuit to enable the integrated circuit to be adaptable to a range of applications. In addition, the programmable logic may facilitate the interfacing of integrated circuits that may otherwise be incompatible, such as with newer technology. Accordingly, the embedded programmable logic may make integrated circuits more cost efficient to develop because of the expanded applications and lifespan.

By way of introduction, FIG. 1 is a system 10 with at least two integrated circuits. Specifically, as depicted, the system 10 includes a first integrated circuit 12 and a second integrated circuit 14, which may complement the functioning of each other. For example, the second integrated circuit 14 may be a peripheral integrated circuit supporting the first integrated circuit 12 or vice versa. As used herein, the peripheral integrated circuit describes an integrated circuit that supports the functionality of another integrated circuit. Accordingly, the integrated circuits 12 and 14 may be a wide variety of integrated circuits, such as field-programmable gate arrays (FPGA), application-specific integrated circuits (ASIC), system on a chip (SoC), transceivers (e.g., optical module), memory modules and the like.

In addition, the second integrated circuit 14 includes programmable logic 16 and a primary circuitry 18. As depicted, the programmable logic 16 may be embedded in the second integrated circuit 14. As used herein, the primary circuitry 18 describes the base functionality of the second integrated circuit 14. For example, when the second integrated circuit 14 is memory, the primary circuitry 18 may be memory that stores and/or fetches data. To enhance the functionality of the primary circuitry 18, the programmable logic 16 may be programmed to implement functions such as data/address manipulation, configuration/testing, computation, or any combination thereof. The programmable logic 16 may be programmed through various methods. For example, the programmable logic 16 may be programmed via configuration memory. Thus, in some embodiments, the programmable logic 16 may be a field programmable gate array (FPGA) fabric available from Altera Corporation, of San Jose, California. Alternatively, the programmable logic 16 may be programmed via metal programmable logic. Thus, in some embodiments, the programmable logic 16 may be HardCopy ASICs, available from Altera Corporation, of San Jose, California. Accordingly, it should be appreciated that the method used to program the programmable logic 16 may enable the programmable logic 16 to be statically or dynamically programmed. For example, the programmable logic 16, similar to an FPGA, may be dynamically programmed/reprogrammed during operation. Specifically, the programmable logic may be wholly or partially programmed during operation. On the other hand, the programmable logic 16 may also be statically programmed during power up to retain the same programming during operation.

Furthermore, as depicted, the first integrated circuit 12 and the second integrated circuit 14 are communicatively coupled. In some embodiments, the system 10 may utilize a configuration in which the first integrated circuit 12 and the

second integrated circuit **14** are both coupled to a printed circuit board (PCB) through a wire bonding process. An alternative configuration, as depicted in FIG. 2, may communicatively couple the first integrated circuit **12** and the second integrated circuit **14** via an interposer **20** (e.g., in a 2.5D configuration). Specifically, the first integrated circuit **12** and the second integrated circuit **14** may communicate through microbumps **22** joined to the interposer **20**. The microbumps **22** connect the integrated circuits **12** and **14** to chip-to-chip interconnects **24** within the interposer **20**. These chip-to-chip interconnects **24** provide communication channels through various depths of the interposer **20**. In some embodiments, as depicted, the interposer **20** may be an active interposer, which enables the programmable logic **16** to be embedded within the interposer **20**. Additionally or alternatively, the interposer **20** may be a passive interposer and the programmable logic **16** may be embedded in the second integrated circuit **14**. Furthermore, through-silicon vias (TSVs) **23** may connect certain of the microbumps **22** and/or chip-to-chip interconnects **24** to C4 interconnects **25**.

Another alternate configuration of the system **10** is depicted in FIG. 3. As depicted, the second integrated circuit **14** is stacked on the first integrated circuit **12** (i.e., in a 3D configuration). Similar to the embodiment depicted in FIG. 2, the programmable logic **16** may be located between the first integrated circuit **12** and the second integrated circuit **14** (i.e., embedded between the integrated circuits **12** and **14**). In addition, microbumps **22** may be used to connect the integrated circuits **12** and **14** to the programmable logic **16**. Although not explicitly depicted, it should be appreciated that chip-to-chip interconnects and/or TSVs may run through the programmable logic **16** to provide communication channels between the integrated circuits **12** and **14**. Alternatively, the programmable logic **16** may be included in the second integrated circuit **14** similar to FIG. 1, and the integrated circuits **12** and **14** may be directly interconnected via microbumps and/or TSVs.

Utilizing one of the above described configurations or another suitable integrated circuit configuration, the first integrated circuit **12** is communicatively coupled to the second integrated circuit **14**, such as a memory module **14A**, which is depicted in FIG. 4. The memory module **14A** may be a single memory die, memory dies stacked with programmable logic, or a stack of memory with embedded programmable logic. In addition, the memory **14A**, for example, may be static random-access memory (SRAM), dynamic random-access memory (DRAM), thyristor random-access memory (T-RAM), or any combination thereof. As depicted, the memory **14A** includes the programmable logic **16**, a configuration port **26**, and the primary circuitry **18**. As used herein, the primary circuitry **18** refers to the components of the integrated circuit that facilitate the base functions of the integrated circuits. For example, in the memory **14A**, the primary circuitry **18** may perform the reading and writing to the memory **14A**. Accordingly the memory module **14A** may complement and/or support the functionality of an FPGA, an ASIC, or the like (i.e., a peripheral integrated circuit).

In addition, as described above, the first integrated circuit **12** and the memory module are coupled, which may enable the integrated circuits **12** and **14** to communicate address signals, data signals, command signals, control signals, configuration signals, or any combination thereof. Specifically, the address signals may specify an address to read and/or write data, which may be communicated via an address bus **13**. Similarly, the data read or to be written may be included in the data signals and communicated via a data

bus **15**. Furthermore, the control signals and command signals may be communicated via a control bus **17** and a command bus **19**. Thus, for example, the first integrated circuit **12** may instruct the memory **14A** to perform a specific action, such as reading data at a memory address. In addition, the configuration signals may be communicated via configuration buses **28**. As will be described in more detail below, the configuration signals may include instructions to configure the integrated circuits **12** and **14**. As depicted, the configuration bus **28** is coupled to the first integrated circuit **12**, to the memory **14A**, and between the two. Accordingly, the first integrated circuit **12** may receive configuration signals from another device, such as a supervising controller, which instructs the first integrated circuit **12** to transmit a second configuration signal to the memory **14A**. Additionally or alternatively, the first integrated circuit **12** may determine itself to send configuration signals to the memory **14A**. Likewise, in some embodiments, the memory **14A** may directly receive configuration signals from another device. Accordingly, the configuration signals may be communicated between the integrated circuits **12** and **14** or from a controlling device, such as an operator utilizing a computing device to communicate with the integrated circuits **12** and **14**.

As described above, the programmable logic **16** may be programmed to enhance the base functions of the memory **14A**. Specifically, the programmable logic **16** may implement data/address manipulation functions, configuration/testing functions, computational functions, or any combination thereof. In the memory module, the data/address manipulation functions may include incrementing/decrementing memory addresses, caching data, configuring memory ports, configuring memory modes, controlling the memory, or any combination thereof. The computational functions may include matching patterns, determining statistics, or any combination thereof. The configuration/testing functions may include built-in self-tests, debugging, performance characterization during wafer sort or final testing, or any combination thereof. To facilitate implementing these enhanced functions on the memory **14A** the programmable logic **16** may be programmed accordingly through configuration signals. Specifically, the memory **14A** may receive configuration signals at the configuration port **26**, which is communicatively coupled to the configuration busses **28** carrying the configuration signals.

For example, FIG. 5 illustrates a process **30** for performing functions (e.g., data/address manipulation functions, configuration/testing functions, computational functions) on the second integrated circuit (e.g., memory **14A**) **14**. The process **30** may begin by coupling the first integrated circuit **12** and the second integrated circuit **14** (process block **32**). As described above, the first integrated circuit **12** and the second integrated circuit **14** may be coupled in various manners, such as through to a printed circuit board (PCB) or through an interposer **20**. Next, the second integrated circuit **14** may receive configuration signals (process block **34**). Specifically, the configuration signals may include instructions relating to the function. Accordingly, the configuration signals may be transmitted to the second integrated circuit **14** from the first integrated circuit **12** or another device based on the function to be implemented in the integrated circuits **12** and **14**. Based on the configuration signals, the second integrated circuit **14** may program the function on the programmable logic **16** (process block **36**). For example, the programmable logic **16** may be programmed to increment/decrement memory addresses, cache data, configure memory ports, configure memory modes/technologies, controlling the memory, or any combination thereof. It should

be appreciated that alternatively block 32 may follow blocks 34 and 36. In other words, the programmable logic 16 may be programmed before being coupled to the first integrated circuit 12. Finally, the programmable logic 16 may perform the function (process block 38).

To further illustrate implementing functions on the programmable logic, a process 40 for implementing a data/address function (i.e., configuring memory modes and/or memory ports) is depicted in FIG. 6. Specifically, the memory modes and/or memory ports may facilitate the functionality of the first integrated circuit 12. As with process 30, process 40 may begin by coupling the first integrated circuit and the memory 14A (process block 42). In addition, the memory 14A may receive configuration signals (process block 44). For example, the first integrated circuit 12 (e.g., an FPGA or an ASIC) may send configuration signals to the memory 14A, via the configuration bus 28, to instruct the configuration of the memory 14A.

Finally, the programmable logic 16 may be programmed (process block 45) and configure the memory mode(s) and/or memory port(s) accordingly (process block 46). By exploiting the strengths of each memory mode (e.g. SRAM, DRAM, or T-RAM), the memory 14A may be programmed in different modes to better facilitate the functions of the first integrated circuit 12. Specifically, the programmable logic 16 may implement various memory modes in the entire or part of the memory 14A. For example, the programmable logic 16 may configure the entire memory 14A as SRAM, or alternatively, the programmable logic 16 may configure a first portion of the memory 14A to operate as SRAM and a second portion to operate as T-RAM. Similarly, the memory ports may be programmed to alter the read or write bandwidth of the memory 14A based on the functionality of the first integrated circuit 12. Specifically, the programmable logic 16 may configure memory ports as read ports or as write ports. For example, if the memory 14A has four ports, when the first integrated circuit 12 utilizes a larger write bandwidth, the programmable logic 16 may configure three of the memory ports as write ports and one as a read port. Alternatively, if the first integrated circuit 12 utilizes a larger read bandwidth, the programmable logic 16 may configure three of the memory ports as read ports and one as a write port. This configuration may be useful when the first integrated circuit 12 is implementing wireline applications, which utilize a higher read bandwidth than write bandwidth.

In addition to performing data/address functions, the programmable logic 16 embedded in the second integrated circuit 14 (e.g., memory 14A) may perform configuration/testing functions. For example, as depicted in FIG. 7, the programmable logic 16 may facilitate a wafer testing process 48 during wafer sort testing and/or final testing. The process 48 may begin by fabricating the wafer (process block 50). Specifically, this may include fabricating the primary circuitry 18 and embedding the programmable logic 16. Next, the second integrated circuit 14 may receive the configuration signals (process block 52). During wafer testing, the second integrated circuit 14 may receive configuration signals from a central wafer testing device via the configuration bus 28. In other words, the central wafer testing device may transmit configuration signals to the memory 14A instructing the programmable logic 16 on a wafer testing function. For example, the wafer testing functions may include self-tests, debugging, performance characterization, or any combination thereof. Next, the wafer testing function may be programmed into the programmable logic (process block 54). And finally, the programmable logic 16 may perform the wafer testing function (process

block 56). For example, programmable logic 16 may self test the second integrated circuit 14 to determine if the second integrated circuit 14 is functioning properly. Additionally, the programmable logic 16 may be programmed to debug the second integrated circuit 14 when it is not functioning properly.

To further illustrate implementing configuration/testing functions on the memory module 14, FIG. 6 depicts a process 58 for testing the memory's performance and compensating accordingly. For example, it should be appreciated, that as the memory 14A ages, the functioning of the components may begin to regress. Specifically, the capacitors in the memory 14A may begin to store less charge than before. The process 58 may begin by receiving configuration signals (process block 60). The configuration signals may include instructions for characterizing the performance of the memory 14A and instructions to compensate for the performance. Accordingly, the configuration signals may come from the first integrated circuit 12 or another device concerned with the performance of the memory module 14A. For example, a testing device may send configuration signals to various memory modules 14A to test performance of each. Next, the programmable logic 16 may be programmed to run the performance characterization function (process block 62) and the programmable logic 16 may perform the performance characterization function (process block 64). For example, the programmable logic 16 may test each bit to determine whether the memory 14A is properly storing data. Finally, based on the performance characterization, the programmable logic 16 may compensate accordingly (process block 66). For example, if it is determined that the capacitors in the memory 14A are not storing enough charge, the power supplied to the memory module 14A may be increased.

In addition to the memory 14A depicted in FIG. 4, the system 10 may include other embodiments of the second integrated circuit 14. For example, as depicted in FIG. 9, a second integrated circuit 14B may include a chip-to-chip interface. Specifically, the second integrated circuit 14B may be an ASIC or a transceiver (e.g., optical module), such as a Thunderbolt module available from Intel Corporation, of Santa Clara, California. Thus, the second integrated circuit 14B may include a data connection 67 (e.g., an optical connector) to couple with an optical cable. Accordingly the second integrated circuit 14B (e.g., optical module) may complement and/or support the functionality of an FPGA, an ASIC, or the like (i.e., a peripheral integrated circuit).

Similar to the embodiment depicted in FIG. 4, the system 10 depicted in FIG. 4 includes the data bus 15 to transmit data between the first integrated circuit 12 and the second integrated circuit 14B. The system 10 also similarly includes the command bus 19 and the control bus 17 to communicate control signals and command signals between the first integrated circuit 12 and the second integrated circuit 14B. In addition, as depicted, the configuration bus 28 is coupled to the first integrated circuit 12, to the second integrated circuit 14B, and between the two to facilitate the transmission of configuration signals. Also similar to the system 10 depicted in FIG. 4, the second integrated circuit 14B includes the programmable logic 16 to enhance the functionality of the primary circuit, the configuration port 26 to receive configuration signals from the configuration bus 28, and the primary circuitry 18. When, for example, the second integrated circuit 14B is a transceiver (e.g., optical IO module or electrical IO module), the primary circuitry 18 may transmit and receive data from other devices.

Furthermore, as depicted, the first integrated circuit **12** includes a first chip-to-chip interface **68**, such as a first universal interface block (UIB1) **68**, and the second integrated circuit **14B** includes a second chip-to-chip interface **70**, such as a second universal interface block (UIB2) **70**. Different chip-to-chip interfaces (e.g., **68** and **70**) may make it difficult to interface the first integrated circuit **12** and the second integrated circuit **14B** because of differences in synchronization, handshaking, throughput matching, interface protocols, and the like. Accordingly, FIG. **10** depicts a process **72** to perform computational functions (e.g., interfacing functions) to facilitate interfacing the integrated circuits (i.e., **12** and **14B**). As should be appreciated, UIB1 and UIB2 are merely illustrative and the techniques taught herein may be applied to various chip-to-chip interfaces.

The process **72** may begin by coupling the first integrated circuit **12** and the second integrated circuit **14B** (process block **74**). As described above, the integrated circuits (i.e., **12** and **14B**) may be coupled in various manners, such as through a printed circuit board (PCB) or through an interposer **20**. Next, the second integrated circuit **14B** may receive configuration signals (process block **76**). Specifically, the configuration signals may include instructions for performing computational functions, such as converting from UIB1 to UIB2. Accordingly, the configuration signals may be transmitted from the first integrated circuit **12** or another device. For example, if UIB2 is a newer chip-to-chip interface, it may include a backward compatibility function that instructs older chip-to-chip interfaces (e.g., UIB1) on how to interface with UIB2 **70** via the configuration signals. Based on the configuration signals, the programmable logic **16** may be programmed with computational functions (process block **78**). Similar to processes described above (i.e., **30** and **40**), the second integrated circuit **14B** may receive the configuration signals and program the programmable logic **16** before being coupled to the first integrated circuit **12**.

The programmable logic **16** may determine operational parameters for both integrated circuits (i.e., **12** and **14B**) (process block **80**). In other words, the programmable logic **16** determines the operational parameter of the integrated circuits (i.e., **12** and **14B**) that may be interfaced. For example, this may include polling the first integrated circuit **12** and the primary circuitry **18** in the second integrated circuit **14A** for the chip-to-chip interface used in each. Finally, the programmable logic **16** may perform the computational function (e.g., interfacing function) in the second integrated circuit **14B** (process block **82**). Following the example presented above, the programmable logic **16** may absorb interface protocol mismatches between chip-to-chip interfaces (e.g., UIB1 and UIB2) to enable seamless integration. More specifically, the programmable logic **16** may adjust the second integrated circuit **14B** based on the chip-to-chip interface of the first integrated circuit **12**.

Other examples of computational functions may include synchronizing the integrated circuits, facilitating handshaking between the integrated circuits, interface protocol conversion, throughput matching (i.e., aggregation or fanout), and the like. For example, an interface protocol conversion function may convert between an Advanced eXtensible Interface (AXI) interface protocol to an Avalon interface protocol. The AXI interface protocol is available from ARM Holdings PLC, of Cambridge, England, and the Avalon interface protocol is available from Altera Corporation, of San Jose, California. Furthermore, when the second integrated circuit **14B** is a transceiver such as an optical IO module, the computational functions may further include encryption/decryption, encoding/decoding, forward error

correction, signal conditioning, signal detection, and the like. For example, the programmable logic **16** may encrypt data before the primary circuitry **18** sends that data through a data connection **67** (e.g., an optical connector). Conversely, the programmable logic **16** may also decrypt data received from the data connection **67** and pass the decrypted data to the primary circuitry **18**. Accordingly, this may enable the second integrated circuit **14B** (e.g., transceiver) to communicate with integrated circuits utilizing various encryption/decryption protocols.

Furthermore, similar to the memory module **14A** described above, the programmable logic **16** may perform configuration/testing functions in the second integrated circuit **14B**. For example, the programmable logic **16** may also test and maintain the transceiver (e.g., optical module) including the data connection **67**. Accordingly, a process **84** for testing the second integrated circuit **14B** (e.g., transceiver) is depicted in FIG. **11**. The process **84** may begin by receiving configuration signals (process block **86**). As described above, the configuration files may be transmitted from the first integrated circuit **12** or from another device. In addition, the configuration signals may include instructions for testing the transceiver (e.g., optical module). For example, the configuration signals may instruct the programmable logic **16** to determine whether the data connection **67** is properly representing data that is transmitted. Additionally, the configuration signals may also instruct the programmable logic **16** to maintain the second integrated circuit **14B** (e.g., transceiver) in order to reduce the possibility of future malfunctions. The testing functions may be programmed onto the programmable logic **16** (process block **88**). And finally, the programmable logic **16** may test the second integrated circuit **14B** (e.g., transceiver) (process block **90**). Following the example above, the programmable logic may instruct the primary circuitry **18** (e.g., base transceiver) to transmit a known signal and test the data connection **67** to determine if that is in fact what is being transmitted.

As described above, the system **10** may include various embodiments of the second integrated circuit **14**. Another example of the second integrated circuit **14**, as depicted in FIG. **12**, is a system on a chip (SoC) **14C**. Again, similar to the embodiment depicted above, the system **10** includes the data bus **15** to transmit data between the first integrated circuit **12** and the SoC **14C**. Furthermore, the system **10** includes the command bus **19** and the control bus **17** to communicate control signals and command signals between the first integrated circuit **12** and the SoC **14C**. In addition, as depicted, the configuration bus **28** is coupled to the SoC **14C** to facilitate the transmission of configuration signals from another device. Also, the SoC **14C** includes the programmable logic **16** to enhance the functionality of the primary circuitry **18**, the configuration port **26** to receive configuration signals from the configuration bus **28**, and the primary circuitry **18** (i.e., base functions of SoC). Furthermore, as depicted, the first integrated circuit **12** includes the first chip-to-chip interface **68** (e.g., UIB1), and the SoC **14C** includes a second chip-to-chip interface **70** (e.g., UIB2).

As should be appreciated, the SoC **14C** may integrate various computational functions into a single chip. Accordingly, the primary circuitry **18** of the SoC **14C** may include random access memory (RAM) **92**, flash memory **94**, a universal serial bus (USB) **96**, and other components **98**. Specifically, the memory (i.e., RAM **92** and flash memory **94**) may facilitate the SoC **14C** in carry out computational functions and the USB **96** may act as an external interface. In addition, each of these components (i.e., **92**, **94**, **96**, and

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98) may be interconnected via a SoC bus 100. For example, the SoC bus 100 may utilize an interface protocol, such as AXI or Avalon described above. In addition to the components (i.e., 92, 94, 96, and 98) included in the SoC 14C, the SoC 14C may interface with peripheral devices (i.e., first integrated circuit 12) via the data bus 15, the command bus 19, the control bus 17, or any combination thereof. For example, the peripherals may be additional memory or a transceiver (e.g., optical IO module or electrical IO module).

Similar to the embodiments described above, the programmable logic 16 may enhance the functionality of the SoC 14C by performing computational functions (e.g., interfacing functions). For example, to facilitate interfacing the SoC 14C with a peripheral device (i.e., first integrated circuit 12), process 72, depicted in FIG. 10, may be utilized. First, the SoC 14C and the peripheral device 12 may be coupled (process block 74). Next, the SoC 14C may receive configuration signals (process block 76). As depicted in FIG. 12, the SoC 14C may receive the configuration signals from another device via the configuration bus 28. Specifically, the configuration signals may instruct the programmable logic to perform a computational function. For example, one computational function may be to change the interface protocol used on the SoC bus 100 to match the interface protocol used in the peripheral device (i.e., first integrated circuit 12) to facilitate interfacing. For example, the programmable logic 16 may change the interface protocol in the SoC bus 100 to Avalon when the interface protocol used in the peripheral device (i.e., first integrated circuit 12) is Avalon. Based on the configuration signals, the programmable logic 16 may be programmed to perform the computational function (i.e., interfacing function) (process block 78). Once programmed, the programmable logic 16 may determine operational parameters of the peripheral (i.e., first integrated circuit 12) and the SoC 14C (process block 80). Depending on the computational function implemented on the programmable logic 16, the programmable logic 16 may poll for various operational parameters. For example, the programmable logic 16 may poll the interface protocols used in the integrated circuits (i.e., 12 and 14C). Specifically, the programmable logic 16 may poll the primary circuitry 18 in the SoC 14C and the peripheral. Finally, the programmable logic 16 may perform the computational function (process block 82).

In a more specific case, when the peripheral device (i.e., first integrated circuit 12) is memory, process 72 may be utilized to adjust the memory modes the SoC 14C may interface with. For example, the programmable logic 16 may adjust the SoC 14C to working with multiple memory modes (e.g., SRAM, DRAM, or T-RAM) to expand the functionality of the SoC 14C.

It should further be appreciated that although each of the embodiments described above included programmable logic 16 in the second integrated circuit 14, the first integrated circuit 12 may also include programmable logic 16 to implement data/address manipulation functions, configuration/testing functions, computational functions, or any combination thereof. Furthermore, as described above, the programmable logic 16 may be programmed via configuration memory, which may enable the programmable logic 16 to be adjusted even after it has been fabricated. For example, this may enable a user to dynamically adjust the functions of an integrated circuit (e.g., second integrated circuit 14) to account for specific applications, newer technology, malfunctioning components, or the like. Additionally, this may even minimize system downtime by enabling integrated circuit (e.g., second integrated circuit 14) to be programmed

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while still coupled to the system 10. Alternatively, as described above, the programmable logic 16 may be programmed via metal programmable logic, which may enable an integrated circuits manufacturer to adjust the functions of the primary circuitry 18 without redesigning the entire integrated circuit.

While the embodiments set forth in the present disclosure may be susceptible to various modifications and alternative forms, specific embodiments have been shown by way of example in the drawings and have been described in detail herein. However, it should be understood that the disclosure is not intended to be limited to the particular forms disclosed. The disclosure is to cover all modifications, equivalents, and alternatives falling within the spirit and scope of the disclosure as defined by the following appended claims.

What is claimed is:

1. A memory integrated circuit, comprising:

a primary circuit configured to implement a first memory operation; and

an embedded programmable logic configured to implement a second memory operation, wherein the second memory operation is configured to adjust functionality of the primary circuit.

2. The memory integrated circuit of claim 1, wherein the first memory operation comprises fetching data, storing data, or both.

3. The memory integrated circuit of claim 1, wherein the second memory operation comprises an address manipulation function, a data manipulation function, or both.

4. The memory integrated circuit of claim 1, wherein the second memory operation is based at least in part on a communication standard to communicate with an integrated circuit.

5. The memory integrated circuit of claim 4, wherein adjusting functionality of the primary circuit provides compatibility with the communication standard.

6. The memory integrated circuit of claim 1, wherein the embedded programmable logic comprises a field programmable gate array.

7. The memory integrated circuit of claim 6, wherein the field programmable gate array is configurable during operation.

8. The memory integrated circuit of claim 1, wherein the primary circuit comprises one or more memory dies.

9. A memory module, comprising:

a primary circuit configured to provide a reading operation, a writing operation, or both; and

an embedded programmable logic configured to provide a memory operation not provided by the primary circuitry, wherein the memory operation is configurable to support functionality of a peripheral integrated circuit communicating with the memory module.

10. The memory module of claim 9, wherein the peripheral integrated circuit is configured to instruct the memory module to read data at a memory address, write data at the memory address, or both.

11. The memory module of claim 10, wherein the memory operation comprises a data manipulation function, an address manipulation function, or both, to enable the memory module to read the data at the memory address, write the data at the memory address, or both.

12. The memory module of claim 11, wherein the data manipulation function, the address manipulation function, or both, comprise incrementing the memory address, decrementing the memory address, caching data, configuring a memory port, configuring a memory mode, controlling the memory module, or any combination thereof.

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13. The memory module of claim **10**, wherein the memory operation comprises a configuration function, a testing function, or both, to enable the memory module to implement configuring, testing, or both, based on a communication between the peripheral integrated circuit and the primary circuit.

14. The memory module of claim **13**, wherein the configuration function, the testing function, or both, comprise built-in self-tests, debugging, performance characterization during wafer sort or final testing, or any combination thereof.

15. The memory module of claim **10**, wherein the memory operation comprises a computational function to enable the memory module to implement computing based on a communication between the peripheral integrated circuit and the primary circuit.

16. The memory module of claim **15**, wherein the computational function comprises a matching pattern, a statistic, or a combination thereof.

17. A method, comprising:

communicatively coupling a primary circuit of a memory module and an integrated circuit;

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receiving a configuration signal at the memory module to facilitate communication between the memory module and the integrated circuit;

programming a data manipulation function in a programmable logic embedded in the memory module based at least in part on the configuration signal; and

implementing the data manipulation function in the programmable logic.

18. The method of claim **17**, wherein the data manipulation function causes the memory module to provide a memory mode for communicating with the integrated circuit.

19. The method of claim **18**, wherein the memory mode comprises a static random-access memory (SRAM), a dynamic random-access memory (DRAM), a thyristor random-access memory (TRAM), or any combination thereof.

20. The method of claim **17**, wherein programming the programmable logic occurs during operation of the memory module.

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